

1. Scope

This specification is applied to Multilayer Ceramic Chip Capacitor(MLCC) for use in electric equipment for the voltage is ranging from 4V to 50V.

The series suitable for general electrics circuit, telecommunications, personal computers and peripheral, power circuit and mobile application. (This product is compliant with the RoHS & HF.)

2. Parts Number Code

	С)201 B	104	к	016 T	S F	
	(1)	(2) (3)	(4)	(5)	(6) (7)	(8) (9)	
(1)Prod	uct			(5)Cap	acitance Toleranc	e	
Produc	t Code			Code	Tolerance	Nominal Capacitance	Э
С	Mult	ilayer Ceramic	Chip Capacitor	K	± 10.0 %	More Than 10 pF	
(2)Chip				(6)Rate	ed Voltage		
Code	Length×V		nm(inch)	Code	Rate	d Voltage (Vdc)	
0201	0.0	60× 0.30 (.024	4× .011)	016		16	
(3)Temp	erature Chara	acteristics		(7) Tap	ping		
Code	Temperature	Temperature	Temperature	Code		Туре	
	Characteristic	Range	Coefficient	Т	1	Tape & Reel	
В	X5R	-55℃~+85℃	± 15%	(8)Thic	kness		
(4)Capa	citance	unit	:pico farads(pF)	Code	Thic	kness T (mm)	
Code	Nomi	inal Capacitanc	e (pF)	S		0.30±0.03	_
104		100,000.0					
-	re is a decimal p	oint, it shall be e		(9)Spe	cial Code		
•	sh capital letter		× v	Code		Туре	
				F	S	pecial Code	
2 Nomi	nal Canadita	noo and Talar	0.10.00				

3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

Class	Characteristic	Tolerance	Nominal Capacitance
Π	X5R	K (± 10.0 %)	E-3, E-6 series

3.2 E series(standard Number)

Standard No.		Application Capacitance										
E- 3	1.0			2.2			4.7					
E- 6	1	.0	1	.5	2	.2	3	.3	4	.7	6	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

Class	Characteristic	Temperature Range	Reference Temp.
П	X5R (B)	-55℃ ~ +85℃	25°C

5. Storage Condition

Storage Temperature : 5 to 40°C

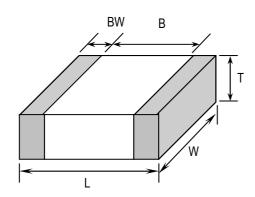
Relative Humidity : 20 to 70 %

Storage Time: 12 months max.



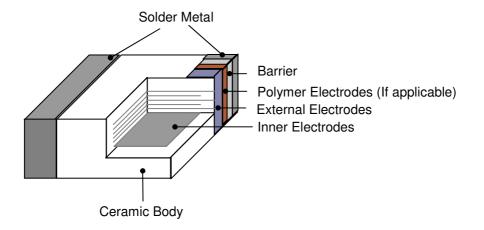
6. Dimensions

6.1 Configuration and Dimension :



					Unit:mm
TYPE	L	W	Т	B (min)	BW (min)
0201	0.60± 0.03	0.30±0.03	0.30± 0.03	0.20	0.10

6.2 Termination Type :





7. Performance

No.	lte	m		Specifica	ation		Test Condition	
1	Vis	ual	No abnorma	al exterior ap	pearance	Visual Inspectior	1	
2	Dime	nsion	See Page 2			Visual Inspection		
3	Insula Resis		500/C Ω min. Applied Voltage: Rated Voltage Charge Time : 60±5 sec. Charge-Discharge current shall be less current.		less than 50mA			
4	Capac	itance	Within The S	Specified Tol	lerance	Class II		
5	Tan δ	Class		X5R: 10% max.		Freq	luency	Voltage
		Ш				X5R	1KHz±10%	1.0±0.2Vrms or 0.5±0.2Vrms
						then place room	emperature at 150 temp. for 24±2hr.	
6	Withsta Volta		No dielectric breakdown	c breakdown	or mechanical	250% of the rated voltage for 1~5 sec. charge/discharge Current is less than 50mA.		sec. an 50mA.
8	Temperature Capacitance Coefficient Adhesive Of Term	e II Strength	X5R -55		Cap. Change(%) ± 15%	C1:Capacitance C2: Capacitance under 1.0Vrms. Pull force shall b 02012N(= 0 0402/060351	N(≕ 0.5 Kg·f)	erature(25°C) ıre (T2)
9		Appear-			ge or capacitance of following table.	≥ 080510N(≒ 1.0 Kg·f)	
		ance	Ũ		e following table.		f the applied forc	es shall be
	Flexure of Substrate	C-Meter	Capacitance Char. X5R (B)	Cap. Chan	ge 5 of initial value	5±1sec	R230 Heter 45±1mm	Bending Limit



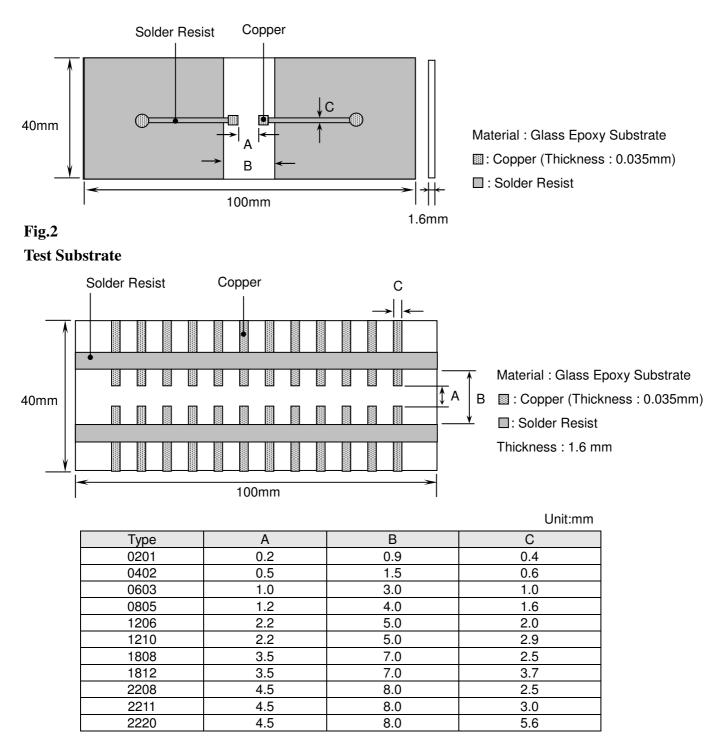
No.	lte	m	S	pecification	Test Condition	
10	Solder	ability	More than 90% of the terminal surface is to be soldered newly, so metal part does not come out or dissolve.		Solder Temperature : $245\pm5^{\circ}$ Dip Time : 5 ± 0.5 sec Immersing Speed : $25\pm10\%$ mm/s Solder : Lead Free Solder Flux :Rosin Preheat : At 80~120 °C for 10~30sec.	
11	Resistance To Soldering Heat	Appear- ance Capacit- ance Tan δ Class ΙΙ Insulation Resistance	No mechanical dama Class II X5R X5R: 10% max. To satisfy the specifi	$\leq \pm 7.5\%$ of initial value	Class II capacitor shall be set for 48 ± 4 hours at room temperature after one hour heat treatment at $150 \pm 0/-10^{\circ}$ C before initial measure. Preheat : at $150\pm10^{\circ}$ C for $60\sim120$ sec. Dip : solder temperature of $260\pm5^{\circ}$ C Dip Time : 10 ± 1 sec. Immersing Speed : $25\pm10\%$ mm/s Flux :Rosin Measure at room temperature after cooling for Class II : 48 ± 4 Hours	
12	Tempera ture Cycle	Appear- ance Capacit- ance Tan δ Class ΙΙ Insulation Resistance	No mechanical dama Class II X5R X5R:10% max. To satisfy the specifi	$\leq \pm 7.5\%$ of initial value	Class II : 48 ± 4 Hours Class II capacitor shall be set for 48±4 hours room temperature after one hour heat treatment at 150 +0/-10°C before initial measure. Capacitor shall be subjected to five cycles of the temperature cycle as following: $\frac{\text{Step Temp.(°C)}}{1 \text{ Min Rated Temp. +0/-3 } 30}$ $2 25 3$ $3 \text{ Max Rated Temp. +3/-0 } 30$ $4 25 3$ Measure at room temperature after cooling for	
13	Humidity	Appear- ance Capacit- ance Tan ∂ Class II Insulation Resistance	No mechanical dama Characteristic Class II X5R X5R: 20% max. 50/C Ω min.	age shall occur. Cap. Change ≤ ±12.5% of initial value	Class II : 48 \pm 4 Hours Class II capacitor shall be set for 48 \pm 4 hours at room temperature after one hour heat treatment at 150 +0/-10 °C before initial measure. Temperature : 40 \pm 2°C Relative Humidity : 90 ~ 95%RH Test Time : 500 Hrs Max. Measure at room temperature after cooling for Class II : 48 \pm 4 Hours	



No.	Iter	m	Spe	cification	Test Condition
14	-	Appear- ance	No mechanical dama	ge shall occur.	Class II capacitors applied DC voltage of the rated voltage is applied for one hour at maximum
		Capacit-	Characteristic	Cap. Change	operation temperature $\pm 3^\circ C$ then shall be set for
		ance		≤ ±12.5% of initial value	48± 4 hours at room temperature and the initial
			X5R	measurement shall be conducted.	
		Tan δ	X5R:20% max.		Applied Voltage :Rated Voltage
		Class II	05/0 0 min		Temperature : 40± 2°C
			25/C Ω min.		Relative Humidity : 90 ~ 95%RH Test Time : 500 Hrs Max.
		Resistance			Current Applied : 50 mA Max.
					Class II capacitor for Cap \geq 103(10nF)
					shall be set for 24±2 hours at room temperature
					after one hour heat treatment at 150 $+0/-10^{\circ}$ C
					before final measure.
					Class
					Measure at room temperature after cooling for
					48 ± 4 Hours.
15	-	••	No mechanical damag	ge shall occur.	The capacitors applied DC testing voltage is
	Temperature				applied for one hour at maximum operation
		Capacit-	Characteristic	Cap. Change	temperature $\pm 3^{\circ}$ C then shell be set for 48± 4
	(Life Test)	ance	Class II	$\leq \pm 12.5\%$ of initial value	1
			X5R		measurement shall be conducted. Applied Voltage: Rated Voltage
		Tan δ	X5R:20% max.		Temperature: max. operation temperature
		Class II			Test Time : 1000 Hrs Max.
			50/C Ω min.		Current Applied : 50mA Max
		Resistance			Class II capacitor for Cap \geq 103(10nF)
					shall be set for 24±2 hours at room temperature
					after one hour heat treatment at $150 + 0/-10^{\circ}C$
					before final measure.
					Class II capacitor for Cap $<$ 103(10nF)
					Measure at room temperature after cooling for
					48 ± 4 Hours.
16	Vibration	Appear- ance	No mechanical damag	ge shall occur	Solder the capacitor on P.C. board.
		Capacit-	Within the specified to	lerance	Vibrate the capacitor with amplitude of
		ance			1.5mm P-P changing the frequencies
		Tan δ	To satisfy the specif	fied initial value	from 10Hz to 55Hz and back to 10Hz in about 1 min.
		Class II			
		Insulation Resistance	To satisfy the specif	fied initial value	Repeat this for 2 hours each in 3 perpendicular directions.



Fig.1 P.C. Board for Bending Strength Test



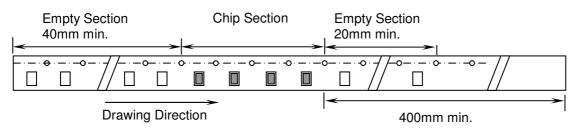


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0201	0402	0603/	0805
Material	T≦0.33mm	T≦0.55mm	$T \leq 1.00 mm$	T>1.00mm
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA
Plastic	NA	NA	NA	3,000 pcs/Reel

Tape		1206	
Material	$T \leq 1.00 mm$	1.00 mm $<$ T \leq 1.25 mm	T>1.25mm
Paper	4,000 pcs/Reel	NA	NA
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel

Tape		1808/1210	
Material	T≦1.25mm	1.25 mm $<$ T \leq 2.40mm	T>2.40mm
Paper	NA	NA	NA
Plastic	3,000 pcs/Reel	1,000/2,000 pcs/Reel	500/1,000 pcs/Reel

Tape	1812/2211/2220		1825/2	2225	2208
Material	T≦2.20mm	T>2.20mm	T≦2.20mm	T>2.20mm	T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1,000 pcs/Reel	700 pcs/Reel	700 pcs/Reel	400 pcs/Reel	1,000 pcs/Reel

NA: Not Available

8.4 Cover Tape Reel Off Force

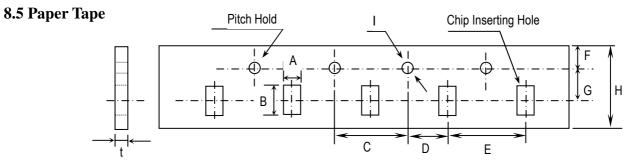
8.4.1 Peel-Off Force

5 g·f \leq Peel-Off Force \leq 70 g·f

8.4.2 Measure Method





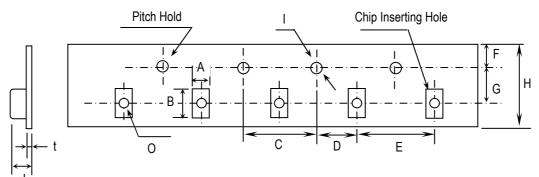


Unit:mm

TYPE	A	В	С	D	E
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н	I	t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	<i>φ</i> 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



Unit:mm

Туре	A	В	С	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				

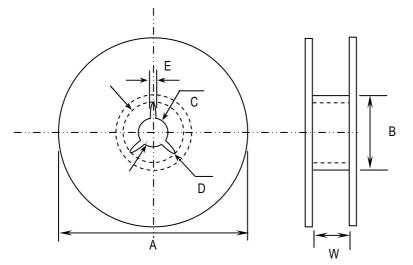


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Туре	G	Н	I	J	t	0
0805	3.5± 0.05	8.0± 0.3	<i>φ</i> 1.5+0.1/-0	3.0 max.	0.3 max.	1.0± 0.1
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		1.5± 0.1
1812						
1825						
2208						
2211						
2220]					
2225						

8.7 Reel Dimensions

Reel Material : Polystyrene



Unit:mm

Туре	А	В	С	D	E	W
0201	φ 382 max	arphi 50 min	φ 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±2.0	arphi 60±2.0				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						



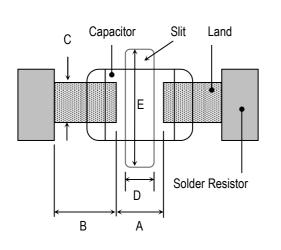
Precautionary Notes:

1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40 °C and 70%RH. We recommend that the capacitors be used within 12 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

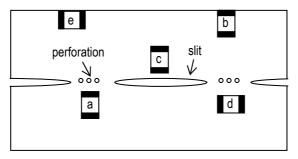
Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table: 2.1 Size and recommend land dimensions for reflow soldering



EIA Code	Chip	(mm)		L	and (mm)		
EIA Coue	L	W	Α	В	С	D	E
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board. Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e





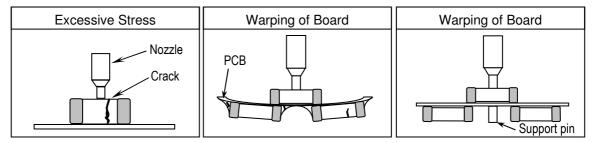
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2.3 Layout Recommendation

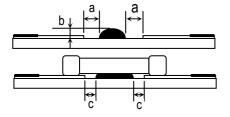
Example	Use of Common Solder Land	Solder With Chassis	Use of Common Solder Land With Other SMD
Need to Avoid	Lead Wire Chip Solder	Chassis Excessive Solder	Solder Land
Recommendation	Lead Wire Chip Solder Resist	Solder Resist	

3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.



3.2 Amount of Adhesive



а	0.2mm min.
b	70 ~ 100 μm
C	Do not touch the solder land

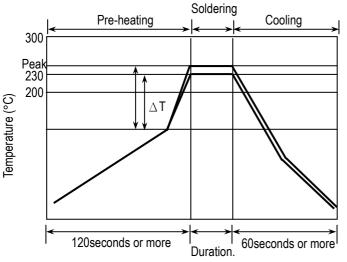


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at Peak Temperature.. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Peak Temp.($^{\circ}$ C) / Duration (sec)
1206 and Under	ΔT ≤ 100~130 max.
Pb-Sn Solder	250°C (max.) / 3sec(max.)
Lead Free Solder	260°C (max.) / 5sec(max.)

Recommended solder compositions

Sn-37Pb (Pb - Sn Solder)

Sn-3.0Ag-0.5Cu (Lead Free Solder)

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

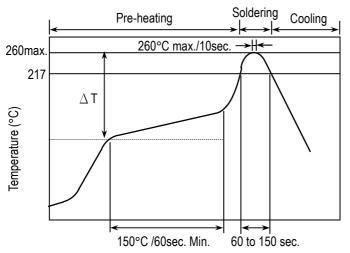
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100 °C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed 3° C/Sec.

Recommend reflow profile for Lead-Free soldering temperature Profile (J-STD-020D)



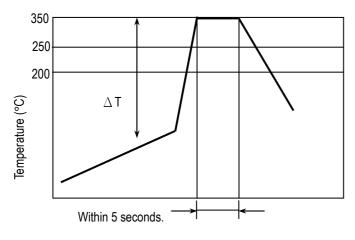
※ The cycles of soldering : Twice (max.)

Soldering Method	Change in Temp.($^\circ C$)
1206 and Under	Δ T \leq 190 $^{\circ}$ C
1210 and Over	∆T ≦ 130 °C



4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.(°C)
1206 and Under	Δ T \leq 150 $^{\circ}$ C
1210 and Over	Δ T \leq 130 $^{\circ}$ C

How to Solder Repair by Solder Iron

1) Selection of the soldering iron tip

The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.

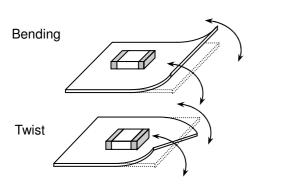
- 2) recommended solder iron condition
 - a.) Preheating Condition : Board and components should be preheated sufficiently at 150 ℃ or over, and soldering should be conducted with soldering iron as boards and components are maintained at sufficient temperatures.
 - b.) Soldering iron power shall not exceed 30 W.

Higher potential of crack

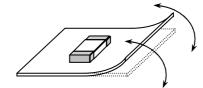
- c.) Soldering iron tip diameter shall not exceed 3mm.
- d.) Temperature of iron tip shall not exceed 350 °C to perform the process within 5 seconds. (refer to MIL-STD-202G)
- f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
- g.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.



Lower potential of crack



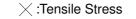
5.2 There is a potential of crack if board is warped due to excessive load by check pin





5.3 Mechanical stress due to warping and torsion.

- (a) Crack occurrence ratio will be increased by manual separation.
- (b) Crack occurrence ratio will be increased by tensile force , rather than compressive force.

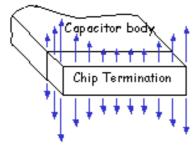


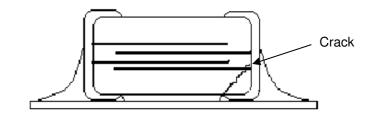
O:Compressive Stress





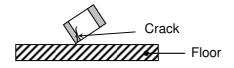
Capacitor Stress Analysis



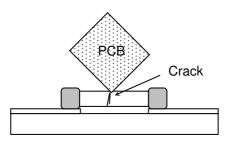


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40 $^{\circ}$ C and under humidity of 20 to 70% RH. The shelf life of capacitors is 12 months.

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